

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	14	(integrated with circuit and test with pin and data with pins and normal adj mode and test adj mode).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 13:24
S2	5	(integrated with circuit and test with pin and data with pins and normal adj mode and test adj mode).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/01 20:52
S3	9	S1 not S2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/01 20:52
S4	3	(sequentially with test with mode with test\$4 with pin and data with pin).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 19:59
S5	5	(sequentially with test with mode with test\$4 with pin and data with pin).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 20:16
S6	7	(sequentially with test with mode with test\$4 with pin and data with pin and normal with mode)".clm,ab."	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 20:17
S7	3	(sequentially with test with mode with test\$4 with pin and data with pin and normal with mode).clm,ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 20:18
S8	0	semiconductor with integrated with circuit same data with output with pins with test with pin with output with signals with data with output with pins same normal with mode with sequentially with clock with signal with test with "mode."	USPAT	OR	OFF	2005/09/02 20:38

S9	0	semiconductor with integrated with circuit same data with output with pins with test with pin with output with signals with data with output with pins same normal with mode with sequentially with clock with signal with test with mode	USPAT	OR	OFF	2005/09/02 20:38
S10	1	semiconductor with integrated with circuit same data with output with pins with test with pin with output with signals with data with output with pins same normal with mode with sequentially with clock with signal with test with mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 20:39
S11	1	semiconductor with integrated with circuit same data with output with pins with test with pin with output with signals with data with output with pins same normal with mode with sequentially with clock with signal with test with mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 20:39
S12	6	324/770.ccls. and test adj mode and normal with mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 20:51
S13	57	sequentially with output\$4 with test\$4 with pin	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 20:52
S14	57	(sequentially with output\$4 with test\$4 with pin)".clm"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 20:52
S15	11	(sequentially with output\$4 with test\$4 with pin).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 20:58
S16	4	sequentially with output\$4 with test\$4 with pin and channel and shift\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 21:11

S17	2	sequentially with output\$4 with data with pin same test adj mode same normal adj mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 21:13
S18	2	sequentially with data with pin same test adj mode same normal adj mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 21:28
S19	5	samsung.as. and sequentially same test adj mode same normal adj mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 21:20
S20	11	sequentially with data with pin same test adj mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/02 21:37
S21	14	sequentially with signal with pin same test adj mode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 21:37
S22	19	("4340857" "4357703" "4377757" "4594711" "4597080" "4701916" "4701920" "4703484").PN. OR ("5043985").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/09/02 21:47
S23	106	"4357703"	USPAT	OR	OFF	2005/09/02 22:01